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PATENT B

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Inventors: Allan Rosencwaig, et al.

Application No.: 09/629,407

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For: MEASUREMENT OF THIN FILMS
AND BARRIER LAYERS ON
PATTERNED WAFERS WITH X-RAY
REFLECTOMETRY

Confirmation No.: 6057

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Examiner: Hoon K. Song

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